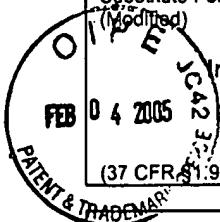


Substitute Form PTO-1449 (Mod/Ted)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-333001	Application No. 10/659,103
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Henry A. Hill	
		Filing Date September 9, 2003	Group Art Unit 1656

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SAT	AA	US 2003/009067 5	05/15/03	Fujiwara			
	AB	US 2002/008967 1	07/11/02	Hill			
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SAT	AY	5,408,318	04/18/95	Slater			

Examiner Signature

S.A. Tuane

Date Considered

12-7-05

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-333001	Application No. 10/659,103
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↑	AAA	5,151,749	09/29/92	Tanimoto et al.			
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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
SAT	AKK	WO 01/90686	11/29/01	WIPO			
SAT	ALL	JP 10-260009 Translation of Abstract Only	09/29/98	Japan			X
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—	APP	JP 9-280822 Translation of Abstract Only	10/31/97	Japan			X

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Signature <i>S.A. Tunga</i>	Date Considered 12-7-05
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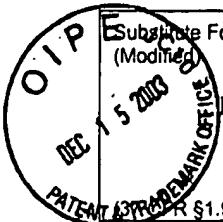
From 10/360.361

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From
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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
	AL						
	AM						
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
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	AR	
	AS	
	AT	

Examiner Signature <i>S.A. Tuniga</i>	Date Considered <i>12-7-05</i>
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